Search Notes			

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/766,035	ANDO ET AL.	
Examiner	Art Unit	
Jeffrey D. Lane	2828	

SEARCHED				
Class	Subclass	Date	Examiner	
372	45.01	1/18/2006	JL	

INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
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SEARCH NOT (INCLUDING SEARCH		)
	DATE	EXMR
Semi-conductor laser with a luminous wavelength	1/18/2006	JL
Semiconductor film layer	1/19/2006	JL
Use of DFB lasers	1/19/2006	JL
Etching of top layers	1/19/2006	JL
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